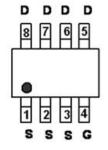
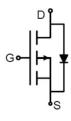


Main Product Characteristics:

V _{DSS}	-30V			
R _{DS} (on)	19.5mΩ (typ.)			
I _D	-7.8A ①			







SOP-8

Pin Assignments

Schematic Diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute Max Rating:

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current ①	-7.8	
I _D @ T _C = 100°C	Continuous Drain Current ①	-4.9	Α
I _{DM}	Pulsed Drain Current ②	-31.2	
P _D @T _A = 25°C	Power Dissipation ③	2.4	W
V _{DS}	Drain-Source Voltage	-30	V
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy @ L=0.5mH	95	mJ
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
Reja	Junction-to-ambient (t \leq 10s) \oplus	_	52	°C/W

Electrical Characteristics @TA=25°C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
V _{(BR)DSS}	Drain-to-Source breakdown voltage	-30	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$	
Б	Ct-ti- Da-is to Course as sistema	_	19.5	25	mΩ	V_{GS} =-10 V , I_D = -7.5 A	
$R_{DS(on)}$	Static Drain-to-Source on-resistance	_	31	41	mΩ	V _{GS} =-4.5V,I _D =-5A	
V _{GS(th)}	Gate threshold voltage	-1	_	-2.5	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	
I _{DSS}	Drain-to-Source leakage current	_	_	-1	μA	V _{DS} = -30V,V _{GS} = 0V	
	Cata to Source forward lookage	_	_	100	nA		V _{GS} = 20V
I _{GSS}	Gate-to-Source forward leakage	_	_	-100		V _{GS} = -20V	
Qg	Total gate charge	_	22	_		I _D = -20A,	
Q _{gs}	Gate-to-Source charge	_	1.5	_	nC	V _{DS} =-15V,	
Q _{gd}	Gate-to-Drain("Miller") charge	_	4	_		V _{GS} = -10V	
t _{d(on)}	Turn-on delay time	_	12	_			
tr	Rise time	_	14	_		V _{GS} =-10V, V _{DS} =-15V,	
t _{d(off)}	Turn-Off delay time	_	195	_	ns	R_{GEN} =3 Ω , R_L =0.75 Ω	
t _f	Fall time	_	95	_			
C _{iss}	Input capacitance	_	1130	_		V _{GS} = 0V	
Coss	Output capacitance	_	185	_	pF	V _{DS} =-15V	
C _{rss}	Reverse transfer capacitance	_	115	_		f = 1MHz	

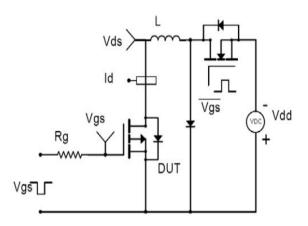
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current	_	_	-7.8	А	MOSFET symbol □ 1
	(Body Diode) ①					showing the
Ism	Pulsed Source Current	_	_	-31.2	А	integral reverse G→
	(Body Diode) ①					p-n junction diode
V _{SD}	Diode Forward Voltage	_	_	-1.2	V	I _S =-20A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	36	_	ns	T _J = 25°C, I _F =-10A,
Qrr	Reverse Recovery Charge	_	34	_	nC	di/dt = 100A/μs

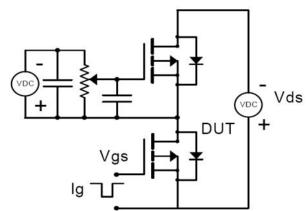


Test Circuits and Waveforms

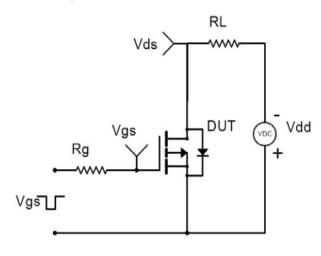
EAS Test Circuit:



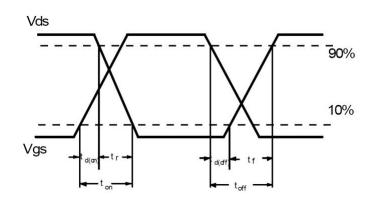
Gate Charge Test Circuit:



Switching Time Test Circuit:



Switching Waveforms:

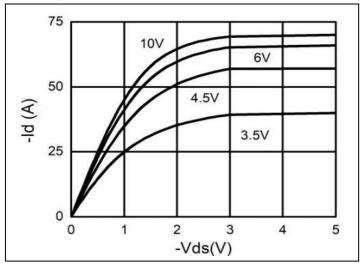


Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C



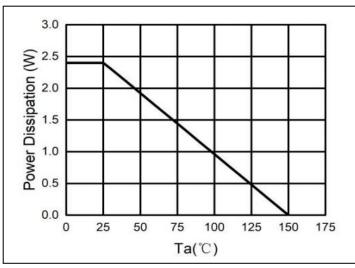
Typical Electrical and Thermal Characteristics



1.3 Vgs=0V Id=-250µA 1.1 Periodic in the second of th

Figure 1. Typical Output Characteristics

Figure 2. BVDSS vs Junction Temperature



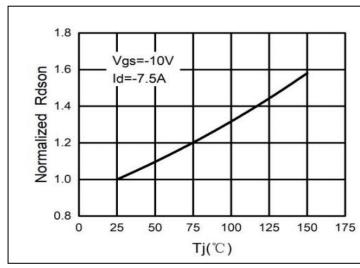
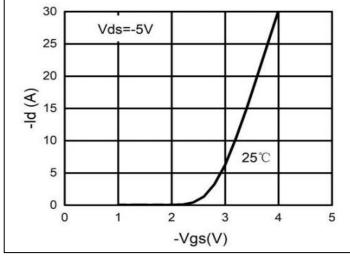


Figure 3. Power Dissipation

Figure 4. RDS(ON) vs Junction Temperature



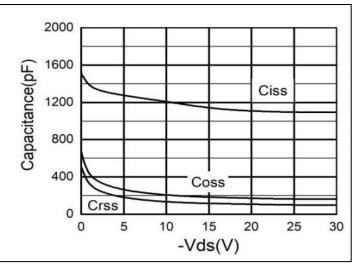
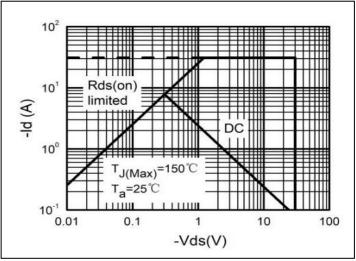


Figure 5. Transfer Characteristics

Figure 6. Capacitance Characteristics



Typical Electrical and Thermal Characteristics



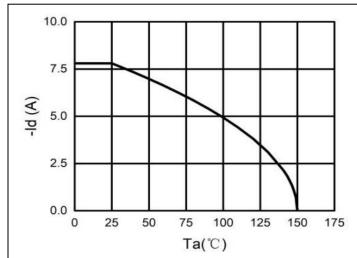
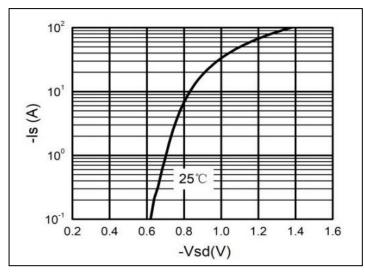


Figure 7. Safe Operation Area





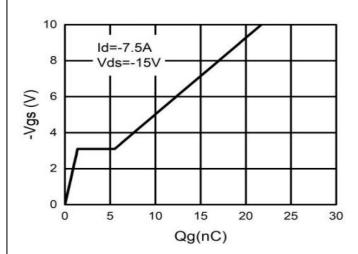


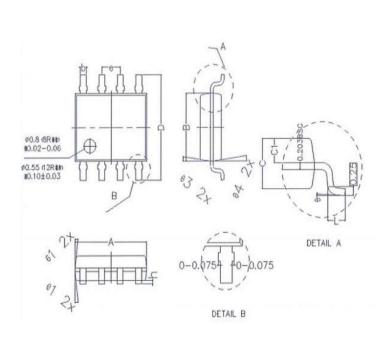
Figure 9. Body Diode Characteristics

Figure 10. Gate Charge



Mechanical Data:

SOP-8 Package Outline (Unit:mm)



		DIMENSIONS MEASURE IS m	m)		
	MIN	NORMAL	MAX		
Α	4.800	4.900	5.000		
В	3.800	3.900	4.000		
C	1.350	1.450	1.550		
C1	0.650	0.700	0.750		
D	5.950	6.120	6.280		
L	0.500	0.600	0.700		
b	0.350	0.400	0.450		
h	0.070	0.150	0.250		
е	1.270TYPE				
θ1	7' TYPE(8R) 12' TYPE(12R)				
θ2	7' TYPE(8R) 10' TYPE(12R)				
θз	8' TYPE(8R) 12' TYPE(12R)				
θ4	8' TYPE(8R) 10' TYPE(12R)				
θ	0° ~ 8°				





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